

ABSTRACT OF THE DISCLOSURE

A semiconductor testing apparatus and a semiconductor testing method are provided which permit an apparatus having an inexpensive configuration to perform, with precision, the acceptance-or-rejection determination and measurement test of a semiconductor integrated circuit having a large number of output terminals each for outputting a multi-gradation level output voltage.

The semiconductor testing apparatus ^{includes} comprises output voltage testing ^{device} means and comparison voltage generation data inputting ^{device} means. The output voltage testing ^{device} means ^{device includes} comprises test voltage inputting ^{device} means, comparison voltage generating ^{device} means, a high level comparator, a low level comparator, and comparison result outputting ^{device} means. The high level comparator and the low level comparator constitute comparing ^{device} means for comparing a voltage to be tested, with a comparison voltage.

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